

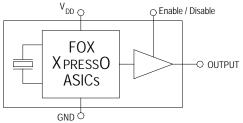
Model: FXO-LC33 SERIES

Freq: 0.75 MHz to 1.35GHz

LVDS 3.2 x 2.5mm 3.3V Oscillator

Features

- XTREMELY Low Jitter
- Low Cost
- XPRESS Delivery
- Frequency Resolution to six decimal places
- Stabilities to ± 25 PPM
- -20 to +70°C or -40 to +85°C operating temperatures
- Tri-State Enable / Disable Feature
- Industry Standard Package, Footprint & Pin-Out
- Fully RoHS and REACH compliant
- Gold over Nickel Termination Finish
- Serial ID with Comprehensive Traceability



For more information -- Click on the drawing

Description

The Fox XPRESSO Crystal Oscillator is a breakthrough in configurable Frequency Control Solutions. XPRESSO utilizes a family of proprietary ASICs, designed and developed by Fox, with a key focus on noise reduction technologies.

The 3rd order Delta Sigma Modulator reduces noise to the levels that are comparable to traditional Bulk Quartz and SAW oscillators. The ASICs family has ability to select the output type, input voltages, and temperature performance features.

With the XPRESS lead-time, low cost, low noise, wide frequency range, excellent ambient performance, XpressO is an excellent choice over the conventional technologies.

Finished XPRESSO parts are 100% final tested. FOXElectronics 5570 Enterprise Parkway Fort Myers, Florida 33905 USA +1.239.693.0099 FAX +1.239.693.1554 http://www.foxonline.com





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Rev. 3/27/2012

Need a

Applications

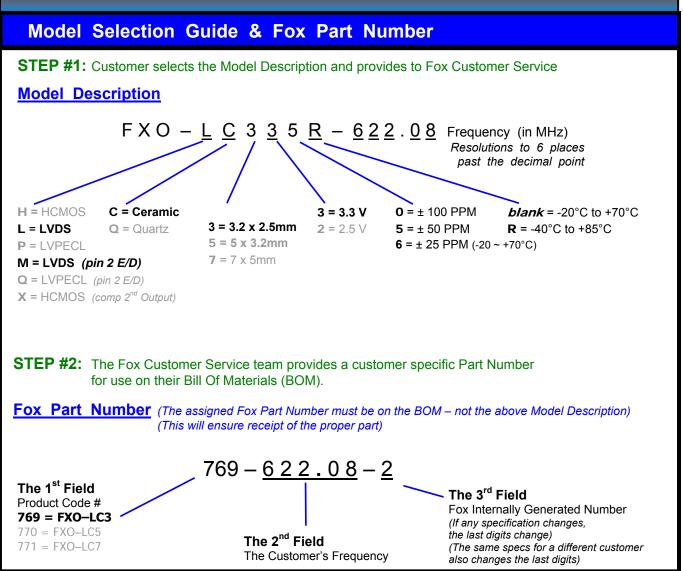
- ANY application requiring an oscillator
- SONET
- Ethernet
- Storage Area Network
- Broadband Access
- Microprocessors / DSP / FPGA
- Industrial Controllers
- Test and Measurement Equipment
- Fiber Channel

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This example, FXO-LC335R-622.08 = LVDS Output, Ceramic, 3.2 x 2.5mm Package, 3.3V, ±50 PPM Stability, -40 to +85°C Temperature Range, at 622.08 MHz





Electrical Characteristics						
Parameters	Symbol	Condition	Maximum Value (unless otherwise noted)			
Frequency Range	Fo		0.750 MHz to 1.35 GHz			
Frequency Stability ¹		0.75 ~ 630.000 MHz (-20 to +70°C) 0.75 ~ 630.000 MHz (-40 to +85°C) 630.000+ MHz ~ 1.350 GHz (-20 to +70°C) 630.000+ MHz ~ 1.350 GHz (-40 to +85°C)	100, 50, 25* PPM 100, 50 PPM 100, 50 PPM 100 PPM			
Temperature Range	Т _о Т _{stg}	Standard operating <i>Optional operating</i> Storage	-20°C to +70°C -40°C to +85°C -55°C to +125°C			
Supply Voltage	V_{DD}	Standard	3.3 V ± 5%			
Input Current (@ 100 Ohm Load)	I _{DD}	Standard Load	100 mA			
Output Load		Standard	100 Ohms Typ.			
Start-Up Time	Ts		10 mS			
Output Enable / Disable Time			100 nS			
Moisture Sensitivity Level	MSL	JEDEC J-STD-20	1			
Termination Finish			Au			

¹¹nclusive of 25°C tolerance, operating temperature range, input voltage change, load change, aging, shock and vibration. *Excludes aging.

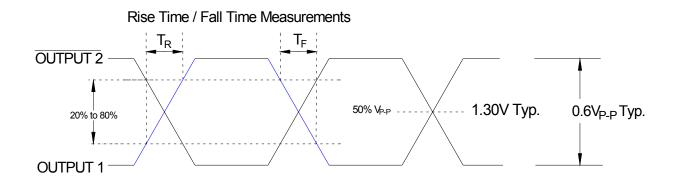
•• Absolute Maximum Ratings (Useful life may be impaired. For user guidelines only, not tested)							
Parameters	Symbol	Condition	Maximum Value (unless otherwise noted)				
Input Voltage	V _{DD}		–0.5V to +5.0V				
Operating Temperature	T _{AMAX}		–55°C to +105°C				
Storage Temperature	T _{STG}		–55°C to +125°C				
Junction Temperature			150°C				
ESD Sensitivity	HBM	Human Body Model	> 1 kV				



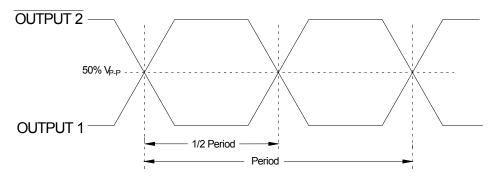


Output Wave Characteristics						
Parameters	Symbol	Condition	Maximum Value (unless otherwise noted)			
Differential Output Voltage	V _{OD}	0.75 MHz to 1.35 GHz	0.6V Typ.			
Output Offset Voltage	V _{os}	Volts DC	1.3V Typ.			
Output Symmetry (See Drawing Below)		@ 50% V _{P-P} Level	45% ~ 55%			
Output Enable (PIN # 1) Voltage Note1	V _{IH}		≥ 70% V _{DD}			
Output Disable (PIN # 1) Voltage Note1	VIL		$\leq 30\% V_{DD}$			
Cycle Rise Time (See Drawing Below)	T _R	20%~80% Vp-p	400 pS			
Cycle Fall Time (See Drawing Below)	T _F	80%~20% Vp-p	400 pS			

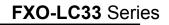
Note1 An optional PIN # 2 as Enable / Disable is available – see Model Selection Guide (page 2)



Oscillator Symmetry Ideally, Symmetry should be 50/50 for 1/2 period – Other expressions are 45/55 or 55/45

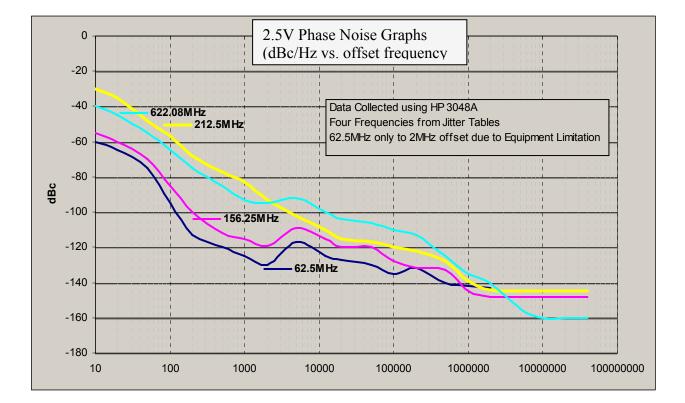








Phase Noise



Jitter is frequency dependent. Below are typical values at select frequencies.

LVDS Phase Jitter & Time Interval Error (TIE)							
Frequency	Phase Jitter (12kHz to 20MHz)	TIE (Sigma of Jitter Distribution)	Units				
62.5 MHz	1.3	2.6	pS RMS				
156.25 MHz	0.6	4.3	pS RMS				
212.5 MHz	0.8	5.0	pS RMS				
622.08MHz	0.7	2.4	pS RMS				

 Phase Jitter
 is integrated from HP3048 Phase Noise Measurement System; measured directly into 50 ohm input; V_{DD} = 3.3V.

 TIE
 was measured on LeCroy LC684 Digital Storage Scope, directly into 50 ohm input, with Amherst M1 software; V_{DD} = 3.3V.

 Per MJSQ spec
 (Methodologies for Jitter and Signal Quality specifications)

LVDS Random & Deterministic Jitter Composition							
Frequency	Random (Rj) (pS RMS)	Deterministic (Dj) (pS P-P)	Total Jitter (Tj) (14 x Rj) + Dj				
62.5 MHz	1.2	11.9	29.1 pS				
156.25 MHz	1.2	11.2	28.4 pS				
212.5 MHz	1.2	12.7	29.8 pS				
622.08 MHz	1.0	9.4	24.5 pS				

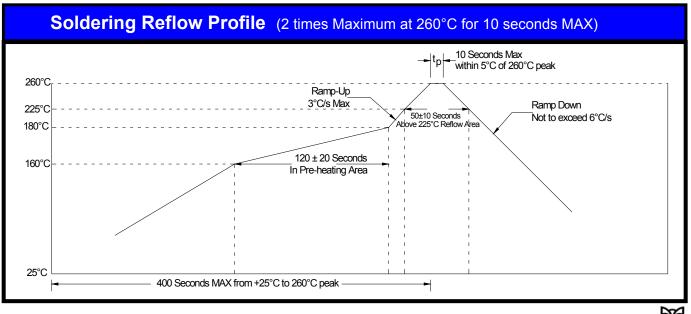
<u>**Rj and Dj**</u>, measured on LeCroy LC684 Digital Storage Scope, directly into 50 ohm input, with Amherst M1 software. Per **MJSQ** spec (Methodologies for Jitter and Signal Quality specifications)





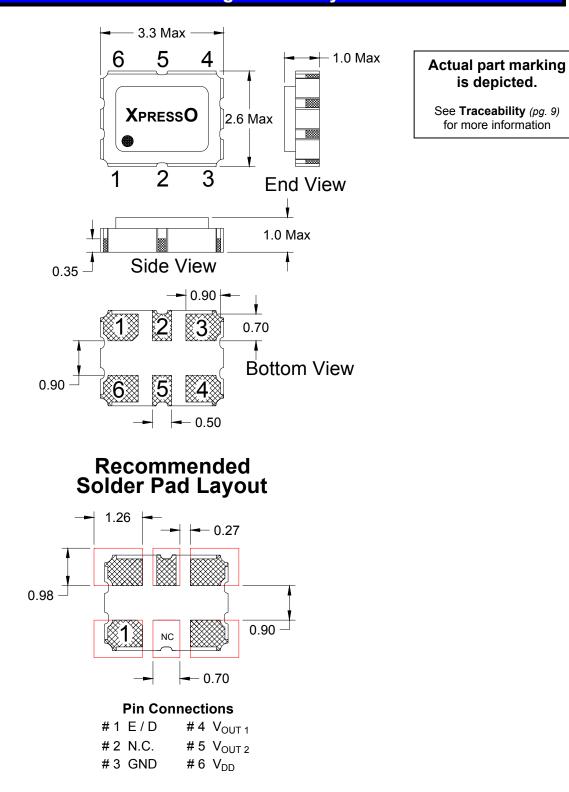
Pin Description and Recommended Circuit					
Pin #	Name	Туре	Function		
1	E/D ¹	Logic	Enable / Disable Control of Output (0 = Disabled)		
2	NC		No Connection – Leave OPEN		
3	GND	Ground	Electrical Ground for V _{DD}		
4	Output	Output	LVDS Oscillator Output		
5	Output 2	Output	Complementary LVDS Output		
6	V_{DD}^{2}	Power	Power Supply Source Voltage		
			 bypass capacitor placed between V_{DD} power supply line noise. 		
E/D		DD	$E/D \bigcirc \# 1 \# 6 \bigcirc 0.01 \mu F \bigvee_{V_{DD}} V_{DD}$		
NC 2 GND 3		utput 2 utput	N C ○ # 2 # 5 OUTPUT		
	tions as viewed		GND # 3 # 4 → OUTPUT		

Enable / Disable Control	
Pin # 1 (state)	Output (Pin # 4, Pin # 5)
OPEN (No Connection)	ACTIVE Output
"1" Level V _{IH} ≥ 70% V _{DD}	ACTIVE Output
"0" Level $V_{IL} \le 30\% V_{DD}$	High Impedance





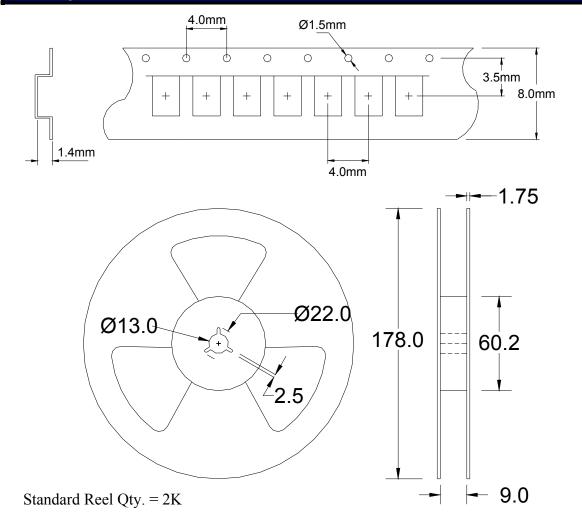
Mechanical Dimensional Drawing & Pad Layout



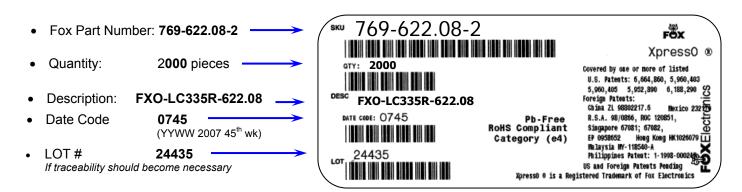
Drawing is for reference to critical specifications defined by size measurements. Certain non-critical visual attributes, such as side castellations, reference pin shape, etc. may vary



Tape and Reel Dimensions



Labeling (Reels and smaller packaging are labeled with the below)



An additional identification code is contained internally if tracking should ever be necessary





Traceability – LOT Number & Serial Identification

LOT Number

The LOT Number has direct ties to the customer purchase order. The LOT Number is marked on the "Reel" label, and also stored internally on non-volatile memory inside the XPRESSO part. XPRESSO parts that are shipped Tape and Reel, are also placed in an Electro Static Discharge (ESD) bag and will have the LOT Number labeled on the exterior of the ESD bag.

It is recommended that the XPRESSO parts remain in this ESD bag during storage for protection and identification.

If the parts become separated from the label showing the LOT Number, it can be retrieved from inside one of the parts, and the information that can be obtained is listed below:

- Customer Purchase Order Number
- Internal Fox Sales Order Number
- Dates that the XPRESSO part was shipped from the factory
- The assigned customer part number
- The specification that the part was designed for

Serial Identification

The Serial ID is the individualized information about the configuration of that particular XPRESSO part. The Serial ID is unique for each and every XPRESSO part, and can be read by special Fox equipment.

With the Serial ID, the below information can be obtained about that individual, XPRESSO part:

- Equipment that the XPRESSO part was configured on
- Raw material used to configure the XPRESSO part
- Traceability of the raw material back to the foundries manufacturing lot
- Date and Time that the part was configured
- Any optimized electrical parameters based on customer specifications
- Electrical testing of the actual completed part
- Human resource that was monitoring the configuration of the part

Fox has equipment placed at key Fox locations World Wide to read the Lot Identification and Serial Number of any XPRESSO part produced and can then obtain the information from above within 24 hours





Party (SGS) Material Report

3rd

Test Report No.: CE/2008/63138 Date: 2008/06/19 Page: 1 of 4 FOX ELECTRONICS 5570 ENTERPRISE PARKWAY FT. MYERS, FL 33905, USA The following sample(s) was/were submitted and identified by/on behalf of the client as : Sample Description : XPRESSO CERAMIC OSCILLATORS Style/Item No. : SEAM SEAL CLOCK OSCILLATOR Buyer/Order No. : 47454 Sample Receiving Date : 2008/06/12 Testing Period : 2008/06/12 TO 2008/06/19 ______ Test Result(s) Please refer to next page(s). : Chenyu Kung / Operation Manager Signed for and on behalf of SGS TAIWAN LTD. **Chemical Laboratory – Taipei** Unless otherwise stated the results shown in this test report refer only to the sample(s) tested. This test report cannot be reproduced, except in full, without prior written permission of the Company. 除非为有我明,此能告结果做到做就之体品负责,本种最大都不公司書面許可,不可能的機要。 This Test Report is issued by the Company under its General Conditions of Service printed overleaf or available on request and accessible at <u>intru-wave ops com/tems</u>, and <u>conditions time</u>. Attention is drawn to the limitation of liability, indemrification and jurisdiction issues defined therein. Any holder of this Test Report is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of Client's instructions, if any. The Company's sole responsibility is to its Client and this document does not exponse parties to a transaction from exercising all their rights and obligations under the transaction documents. Any under the transaction documents, any unauthorized ateration, forgery or tailsfication of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. SGS Taiwan Ltd. No. 33 Wu Chyuan Road, Wuku Industrial Zone, Taipel County, Taiwan / 台北朝江股工業高五補路 33號 科技股份有限公司 t (886-2) 2299-3339 f (886-2) 2299-3237 www.twisgs.com f (886-2) 2299-3237 台灣檢驗科技股份有限公司_ Member of the SGS Group





FXO-LC33 Series

3rd Party (SGS) Material Report (continued)



Test Report

No.: CE/2008/63138 Date: 2008/06/19 Page: 2 of 4

FOX ELECTRONICS 5570 ENTERPRISE PARKWAY FT. MYERS, FL 33905, USA

Test Result(s)

PART NAME NO.1

: MIXED ALL PARTS

Test Item (s):	Unit	Method	MDL	Result
10000000000000000000000000000000000000	Unit		10000	No.1
Cadmium (Cd)	mg/kg	With reference to IEC 62321/2nd CDV (111/95/CDV). Determination of Cadmium by ICP-AES.	2	n.d.
Lead (Pb)	mg/kg	With reference to IEC 62321/2nd CDV (111/95/CDV). Determination of Lead by ICP-AES.	2	n.d.
Mercury (Hg)	mg/kg	With reference to IEC 62321/2nd CDV (111/95/CDV). Determination of Mercury by ICP-AES.	2	n.d.
Hexavalent Chromium Cr(VI) by alkaline extraction	mg/kg	With reference to IEC 62321/2nd CDV (111/95/CDV). Determination of Hexavalent Chromium for non- metallic samples by UV/Vis Spectrometry.	2	n.d.
Halogen		With reference to BS EN 14582:2007. Analysis was performed by IC method for F, CI, Br, I content.		
Halogen-Fluorine (F) (CAS No.: 007782-41-4)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for Fluorine content.	50	n.d.
Halogen-Chlorine (Cl) (CAS No.: 007782-50-5)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for Chlorine content.	50	n.d.
Halogen-Bromine (Br) (CAS No.: 007726-95-6)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for Bromine content.	50	n.d.
Halogen-lodine (I) (CAS No.: 007553-56-2)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for lodine content.	50	n.d.

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FXO-LC33 Series

3rd Party (SGS) Material Report (continued)



Test Report

No.: CE/2008/63138 Date: 2008/06/19 Page: 3 of 4

FOX ELECTRONICS 5570 ENTERPRISE PARKWAY FT. MYERS, FL 33905, USA

Test Item (s):	Unit	Method	MDL	Result
	onit	Mediod	MDL	No.1
Sum of PBBs			2 4 6	n.d.
Monobromobiphenyl		Ι Γ	5	n.d.
Dibromobiphenyl	1	I F	5	n.d.
Tribromobiphenyl		I E	5	n.d.
Tetrabromobiphenyl	1	I E	5	n.d.
Pentabromobiphenyl	1	I F	5	n.d.
Hexabromobiphenyl	1	I F	5	n.d.
Heptabromobiphenyl]	I F	5	n.d.
Octabromobiphenyl	1	I F	5	n.d.
Nonabromobiphenyl	1	With reference to IEC 62321/2nd CDV (111/95/CDV). Determination of PBB and PBDE by GC/MS.	5	n.d.
Decabromobiphenyl			5	n.d.
Sum of PBDEs (Mono to Nona)	mg/kg		-	n.d.
Monobromodiphenyl ether			5	n.d.
Dibromodiphenyl ether	1		5	n.d.
Tribromodiphenyl ether	1		5	n.d.
Tetrabromodiphenyl ether	1	I F	5	n.d.
Pentabromodiphenyl ether	1	1 1	5	n.d.
Hexabromodiphenyl ether	1	I F	5	n.d.
Heptabromodiphenyl ether	1		5	n.d.
Octabromodiphenyl ether			5	n.d.
Nonabromodiphenyl ether			5	n.d.
Decabromodiphenyl ether			5	n.d.
Sum of PBDEs (Mono to Deca)	1	I F	(1 1)	n.d.

Note: 1. mg/kg = ppm

2. n.d. = Not Detected

3. MDL = Method Detection Limit

4. "---" = Not Conducted

5. " - " = Not Regulated

6. The sample(s) was/were analyzed on behalf of the applicant as mixing sample in one testing. The above result(s) was/were only given as the informality value.

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FXO-LC33 Series

3rd Party (SGS) Material Report (continued)



Test Report

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FOX ELECTRONICS 5570 ENTERPRISE PARKWAY FT. MYERS, FL 33905, USA



** End of Report **

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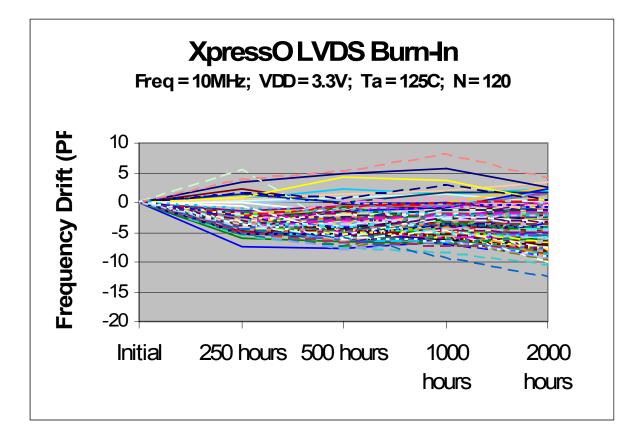


Mechanical Testing

Parameter	Test Method		
Mechanical Shock	Drop from 75cm to hardwood surface – 3 times		
Mechanical Vibration	10~55Hz, 1.5mm amplitude, 1 Minute Sweep 2 Hours each in 3 Directions (X, Y, Z)		
High Temperature Burn-in	Under Power @ 125°C for 2000 Hours (results below)		
Hermetic Seal	He pressure: 4 ±1 kgf / cm ² 2 Hour soak		

2,000 Hour Burn-In

Burn-In Testing – under power 2000 Hours, 125°C







MTTF / FITS Calculations

Products are grouped together by process for MTTF calculations. (All XpressO output and package types are manufactured with the same process)

Number of Parts Tested: 360 (120 of each output type: HCMOS, LVDS, LVPECL) Number of Failures: 0 Test Temperature: 125°C Number of Hours: 2000

MTTF was calculated using the following formulas:

[1.] Device Hours (devhrs) = (number of devices) x (hours at elevated temperature in °K)

[2.] $MTTF = \frac{devhrs \times af \times 2}{\chi^2}$ [3.] FITS = $\frac{1}{MTTF}$ * 10⁹

$$\frac{3.1}{MTT}$$

Where:

WINCIE.			
Label	Name	Formula/Value	
af	Acceleration Factor	$\boldsymbol{\varrho}^{(\frac{eV}{k})\times(\frac{1}{t_1}-\frac{1}{t_2})}$	
eV	Activation Energy	0.40 V	
k	Bolzman's Constant	8.62 X 10⁻⁵ <i>eV</i> /ºK	
t ₁		Operating Temperature (°K)	
t ₂		Accelerated Temperature (°K)	
Θ	Theta	Confidence Level (60% industry standard)	
r	Failures	Number of failed devices	
X ²	Chi-Square	statistical significance for bivariate tabular analysis [table look- up] based on assumed Θ (Theta – confidence) and number of failures (r) For zero failures (60% Confidence): χ^2 = 1.830	

DEVICE-HOURS = 360 x 2000 HOURS = 720,000

ACCELERATION FACTOR = $e^{(\frac{0.40}{8.625}) \times (\frac{1}{298} - \frac{1}{398})} = 49.91009$

MTTF = $\frac{720,000 \times 49.91009 \times 2}{2}$ = 39,209,238 Hours 1.833

Failure Rate = $\frac{1.833}{720,000 \times 49.91009 \times 2}$ = 2.55E-8

FITS = Failure Rate *1E9 = 26





Patent Numbers: US 6,664,860, US 5,960,403, US 5,952,890; US 5,960,405; US 6,188,290; Foreign Patents: R.S.A. 98/0866, R.O.C. 120851; Singapore 67081, 67082; EP 0958652 China ZL 98802217.6, Malaysia MY-118540-A, Philippines 1-1998-000245, Hong Kong #HK1026079, Mexico #232179 US and Foreign Patents Pending XpressO™ Fox Electronics

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The above specifications, having been carefully prepared and checked, is believed to be accurate at the time of publication; however, no responsibility is assumed by Fox Electronics for inaccuracies.

